

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/767,763	OGAWA, HIDEHIKO	
Examiner		Art Unit		Page 1 of 1
Thomas D. Lee		2625		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,221,471	05-2007	Ogawa, Hidehiko	358/1.15
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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